

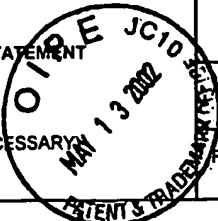
FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMEX 328A	APPLICATION NO. 10/074,633
INFORMATION DISCLOSURE STATEMENT BY APPLICANT			
O P E J C T O MAY 13 2002 PATENT & TRADEMARK OFFICE			
(USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Michael A. Todd	
		FILING DATE February 11, 2002	GROUP 2812

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
LP	4,363,828	12/14/82	Brodsky et al.			
	4,495,218	1/22/85	Azuma et al.			
	4,585,671	4/29/86	Kitagawa et al.			
	4,684,542	8/4/87	Jasinski et al.			
	5,227,329	7/13/93	Kobayashi et al.			
	5,607,724	3/4/97	Beinglass et al.			
	5,614,257	3/25/97	Beinglass et al.			
	5,648,293	7/15/97	Hayama et al.			
	5,656,531	8/12/97	Thakur et al.			
	5,695,819	12/9/97	Beinglass et al.			
	5,700,520	12/23/97	Beinglass et al.			
	5,786,027	7/28/98	Rolfson			
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	5,837,580	11/17/98	Thakur et al.			
	5,874,128	2/23/99	Beinglass et al.			
	5,876,797	3/2/99	Beinglass et al.			
	5,885,869	3/23/99	Turner et al.			
	6,027,705	2/22/00	Kitsuno et al.			11/30/98
	6,083,810	7/4/00	Obeng et al.			12/5/98
✓	6,197,694 B1	3/6/01	Beinglass			7/31/98

FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
LP	57209810 A	12/23/82	Japan			Abstract
J	59078918 A	5/8/84	Japan			Abstract
J	59078919 A	5/8/84	Japan			Abstract

EXAMINER	LONG PHAM	DATE CONSIDERED	9/12/04.
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

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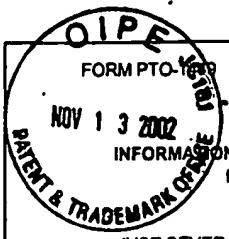


FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
				YES	NO		
L	60043485 A	3/8/85	Japan			Abstract	
	61153277 A	7/11/86	Japan			Abstract	
	62078612 A	4/8/87	Japan			Abstract	
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	03185817 A	8/13/91	Japan			Abstract	
	03187215 A	8/15/91	Japan			Abstract	
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	05021378 A	1/29/93	Japan			Abstract	
	05062911 A	3/12/93	Japan			Abstract	
	07249618 A	9/26/95	Japan			Abstract	
	08242008 A	8/17/98	Japan			Abstract	
	S60-43485	3/8/85	Japan (Patent Disclosure)			X	
	H 02-155225	6/14/90	Japan (Patent Disclosure)			X	
	H3-185817	8/13/91	Japan (Patent Disclosure)			X	
	H3-187215	8/15/91	Japan (Patent Disclosure)			X	
	H3-91239	4/16/91	Japan (Patent Disclosure)			X	
✓	H5-62911	3/12/93	Japan (Patent Disclosure)			X	

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PATENT AND TRADEMARK OFFICE

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APPLICATION NO.
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Michael A. Todd

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2812**

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

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						YES	NO

**EXAMINER
INITIAL**

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

7. Van Zant, Peter, "Microchip Fabrication," 4th Ed., McGraw Hill, New York, (2000), pp. 364-365

8. Van Zant, Peter, "Microchip Fabrication," 4th Ed., McGraw Hill, New York, (2000), p 380-382

9. Van Zant, Peter, "Microchip Fabrication," 4th Ed., McGraw Hill, New York, (2000), pp. 385

10. Van Zant, Peter, "Microchip Fabrication," 4th Ed., McGraw Hill, New York, (2000), pp. 522-526

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